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## Cr ohmic contact on an Ar<sup>+</sup> ion modified 6H-SiC(0001) surface

Milosz Grodzicki, Jan Chrzanowski, Piotr Mazur, Stefan Zuber, Antoni Ciszewski

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### Keywords

silicon carbide, chromium, electric contacts, AFM

### Abstract

Chromium layers were vapor deposited under ultrahigh vacuum onto samples cut out of a single crystal of 6H-SiC (0001) that were Ar<sup>+</sup> bombardment modified. The substrates and electrical contacts formed by the Cr adlayer were characterized *in situ* by current-sensing atomic force microscopy (CS-AFM) and X-ray photoelectron spectroscopy (XPS). Cr/SiC contacts reveal a good *I-V* characteristic linearity without the use of heavy impurity doping and high-temperature annealing.



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